

# INTERNATIONAL SEARCH REPORT

Int. Application No  
PCT/IL2004/000915

<b>A. CLASSIFICATION OF SUBJECT MATTER</b> IPC 7 H01L27/06 H01L27/148 H01L31/02		
According to International Patent Classification (IPC) or to both national classification and IPC		
<b>B. FIELDS SEARCHED</b> Minimum documentation searched (classification system followed by classification symbols) IPC 7 H01L		
Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched		
Electronic data base consulted during the international search (name of data base and, where practical, search terms used) EPO-Internal, INSPEC		
<b>C. DOCUMENTS CONSIDERED TO BE RELEVANT</b>		
Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	TEWKSBURY S K ET AL: "Cointegration of optoelectronics and submicron CMOS" WAFER SCALE INTEGRATION, 1993. PROCEEDINGS., FIFTH ANNUAL IEEE INTERNATIONAL CONFERENCE ON SAN FRANCISCO, CA, USA 20-22 JAN. 1993, NEW YORK, NY, USA, IEEE, US, 20 January 1993 (1993-01-20), pages 358-367, XP010067696 ISBN: 0-7803-0867-0	1,8,11
Y	page 362, line 1 - page 366, line 50; figures 5-9	3,4,6,7, 10,12,14
Y	US 6 416 218 B1 (CHEUNG LIM) 9 July 2002 (2002-07-09) column 1, line 60 - column 3, line 13; figures 2-6 column 5, line 58 - column 8, line 20	3,6,7, 10,12,14
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<input checked="" type="checkbox"/> Further documents are listed in the continuation of box C. <input checked="" type="checkbox"/> Patent family members are listed in annex.		
* Special categories of cited documents : *A* document defining the general state of the art which is not considered to be of particular relevance *E* earlier document but published on or after the international filing date *L* document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified) *O* document referring to an oral disclosure, use, exhibition or other means *P* document published prior to the international filing date but later than the priority date claimed *T* later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention *X* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone *Y* document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art. *&* document member of the same patent family		
Date of the actual completion of the international search  27 January 2005		Date of mailing of the international search report  04/02/2005
Name and mailing address of the ISA European Patent Office, P.B. 5818 Patentlaan 2 NL - 2280 HV Rijswijk Tel. (+31-70) 340-2040, Tx. 31 651 epo nl, Fax: (+31-70) 340-3016		Authorized officer  Boero, M

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## C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	FLACK W W ET AL: "Lithographic manufacturing techniques for wafer scale integration" WAFER SCALE INTEGRATION, 1992. PROCEEDINGS., Y4TH INTERNATIONAL CONFERENCE ON SAN FRANCISCO, CA, USA 22-24 JAN. 1992, LOS ALAMITOS, CA, USA, IEEE COMPUT. SOC, US, 22 January 1992 (1992-01-22), pages 4-13, XP010026528 ISBN: 0-8186-2482-5 the whole document	1-12
P,A	WO 03/083944 A1 (INTERON AS; NYGARD, EINAR; BUTNARO, SHARONA) 9 October 2003 (2003-10-09) the whole document	1-12
Y	WO 02/067014 A1 (REAL-TIME RADIOGRAPHY LTD; HAREL, ZE'EV; SCHIEBER, MICHAEL; SAADO, YEH) 29 August 2002 (2002-08-29)	4
A	page 14, line 1 - page 16, line 12; figures 1,2	1

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Information on patent family members

International Application No

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Patent document cited in search report		Publication date		Patent family member(s)		Publication date
US 6416218	B1	09-07-2002	US	6005911 A		21-12-1999
WO 03083944	A1	09-10-2003	EP	1483790 A1		08-12-2004
WO 02067014	A1	29-08-2002	NONE			